Power MOSFET 30 V, 155 A, Single N-Channel, ICEPAK

Features

- Low Package Inductance
- Low R_{DS(on)} to Minimize Conduction Losses
- Low Capacitance to Minimize Driver Losses
- Optimized Gate Charge to Minimize Switching Losses
- Dual Sided Cooling Capability
- Compatible with MX Footprint and Outline
- These are Pb-Free Devices

Applications

- CPU Power Delivery
- DC-DC Converters
- Optimized for both Synch FET

MAXIMUM RATINGS (T_J = 25°C unless otherwise stated)

Parameter			Symbol	Value	Unit
Drain-to-Source Voltage			V_{DSS}	30	V
Gate-to-Source Voltage			V_{GS}	±20	V
Continuous Drain		T _A = 25°C	Ι _D	32	Α
Current R _{θJA} (Note 1)		T _A = 70°C	1	25.5	
Power Dissipation $R_{\theta JA}$ (Note 1)		T _A = 25°C	P _D	2.8	W
Continuous Drain		T _A = 25°C	I _D	155	Α
Current $R_{\theta J-PCB}$ (Note 2)	Steady State	T _A = 70°C		86	
Power Dissipation R _{θJ-PCB} (Note 2)	State	T _A = 25°C	P _D	65	W
Continuous Drain		T _C = 25°C	I _D	192	Α
Current R _{θJC} (Note 1)		T _C = 70°C		154	
Power Dissipation R _{θJC} (Note 1)		T _C = 25°C	P _D	100	W
Pulsed Drain Current	$T_A = 25^{\circ}C, t_p = 10 \mu\text{s}$		I_{DM}	244	Α
Current Limited by Package T _A = 25°C			I _{Dmax}	50	Α
Operating Junction and Storage Temperature			T _J , T _{stg}	-40 to 150	°C
Source Current (Body Diode) (Note 1)			I _S	128	Α
Drain to Source DV/DT			dV/dt	6.0	V/ns
Single Pulse Drain-to–Source Avalanche Energy ($T_J = 25^{\circ}C$, $V_{DD} = 30$ V, $V_{GS} = 10$ V, $I_L = 58$ A_{pk} , $L = 0.3$ mH, $R_G = 25$ Ω)			E _{AS}	505	mJ
Lead Temperature for Soldering Purposes (1/8" from case for 10 s)			TL	270	°C

Stresses exceeding Maximum Ratings may damage the device. Maximum Ratings are stress ratings only. Functional operation above the Recommended Operating Conditions is not implied. Extended exposure to stresses above the Recommended Operating Conditions may affect device reliability.

- 1. Surfacemounted on FR4 board using 1 sq-in pad, 1 oz Cu.
- 2. Measured with a T_J of approximately 90°C using 1 oz Cu board.
- 3. Surfacemounted on FR4 board using 1 sq-in pad, 2 oz Cu.



ON Semiconductor®

http://onsemi.com

V _{(BR)DSS}	R _{DS(ON)} MAX	I _D MAX
30 V	1.8 mΩ @ 10 V	155 A
30 V	2.5 mΩ @ 4.5 V	13374



ICEPAK E PAD CASE 145AB

MARKING DIAGRAM



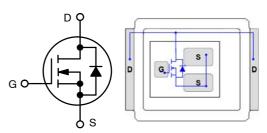
E4890 = Specific Device Code

A = Assembly Location

Y = Year WW = Work Week

= Pb-Free Package

(Note: Microdot may be in either location)



N-CHANNEL MOSFET

ORDERING INFORMATION

Device	Package	Shipping [†]
NTMKE4890NT1G	ICEPAK (Pb-Free)	1500/Tape & Reel
NTMKE4890NT3G	ICEPAK (Pb-Free)	5000/Tape & Reel

[†]For information on tape and reel specifications, including part orientation and tape sizes, please refer to our Tape and Reel Packaging Specification Brochure, BRD8011/D.

THERMAL RESISTANCE MAXIMUM RATINGS

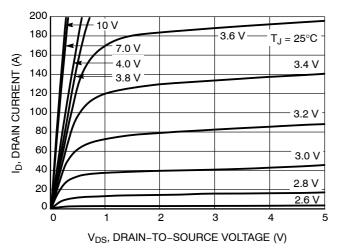
Parameter	Symbol	Value	Unit
Junction-to-Case (Drain) (Note 1)	$R_{ heta JC}$	1.25	°C/W
Junction-to-Ambient - Steady State (Note 1)	$R_{ heta JA}$	45	
Junction-to-Ambient - Steady State (Notes 2 and 3)	$R_{ heta JA}$	25	
Junction-to-PCB (Note 2)	$R_{\theta J-PCB}$	1.0	

ELECTRICAL CHARACTERISTICS (T_{.1} = 25°C unless otherwise specified)

Parameter	Symbol	Test Condition		Min	Тур	Max	Unit
OFF CHARACTERISTICS							
Drain-to-Source Breakdown Voltage	V _{(BR)DSS}	$V_{GS} = 0 \text{ V}, I_D = 250 \text{ p}$	μΑ	30			V
Drain-to-Source Breakdown Voltage Temperature Coefficient	V _{(BR)DSS} /T _J				20		mV/°C
Zero Gate Voltage Drain Current	I _{DSS}	T	_J = 25°C			1.0	μΑ
		$V_{GS} = 0 \text{ V}, V_{DS} = 24 \text{ V}$ T_{c}	_J = 125°C			100	
Gate-to-Source Leakage Current	I _{GSS}	$V_{DS} = 0 \text{ V}, V_{GS} = \pm 20$				±100	nA
ON CHARACTERISTICS (Note 4)							
Gate Threshold Voltage	V _{GS(TH)}	$V_{GS} = V_{DS}, I_D = 250$	μΑ	1.4		2.4	V
Negative Threshold Temperature Coefficient	V _{GS(TH)} /T _J				5.9		mV/°C
Drain-to-Source On Resistance	R _{DS(on)}	V _{GS} = 10 V, I _D = 30	А		1.5	1.8	mΩ
		V _{GS} = 4.5 V, I _D = 30	Α		2.1	2.5	
Forward Transconductance	9FS	V _{DS} = 15 V, I _D = 25	Α		120		S
CHARGES, CAPACITANCES AND GA	ATE RESISTAN	ICE					
Input Capacitance	C _{iss}	V _{GS} = 0 V, f = 1.0 MHz, V _{DS} = 15 V			7100		pF
Output Capacitance	C _{oss}				1360		1
Reverse Transfer Capacitance	C _{rss}				690		
Total Gate Charge	Q _{G(TOT)}				51.7		nC
Threshold Gate Charge	Q _{G(TH)}	V _{GS} = 4.5 V, V _{DS} = 15 V, I _D = 25 A			6.0		
Gate-to-Source Charge	Q _{GS}				18.8		
Gate-to-Drain Charge	Q_{GD}		-		18.6		
Total Gate Charge	Q _{G(TOT)}	V _{GS} = 10 V, V _{DS} = 15 V, I _E	_O = 25 A		104		nC
SWITCHING CHARACTERISTICS (No	ote 5)		•				•
Turn-On Delay Time	t _{d(on)}				25		ns
Rise Time	t _r	V _{GS} = 4.5 V, V _{DS} = 15	5 V.		23		
Turn-Off Delay Time	t _{d(off)}	$I_D = 25 \text{ A}, R_G = 2.0 \Omega$			42		
Fall Time	t _f				12		
DRAIN-SOURCE DIODE CHARACTE	RISTICS		•				•
Forward Diode Voltage	V_{SD}	Т	_J = 25°C		0.78	1.0	V
		$V_{GS} = 0 \text{ V}, I_S = 20 \text{ A}$	ן = 125°C		0.68		
Reverse Recovery Time	t _{RR}				41.8		ns
Charge Time	ta	V_{GS} = 0 V, d_{IS}/d_t = 200 A/ μ s, I_S = 20 A			19.4		
Discharge Time	t _b				22.4		1
Reverse Recovery Charge	Q _{RR}				61		nC
PACKAGE PARASITIC VALUES							
Gate Resistance	R_{G}	T _A = 25°C			0.6	1.5	Ω
		·					

Pulse Test: pulse width = 300 μs, duty cycle ≤ 2%.
 Switching characteristics are independent of operating junction temperatures.

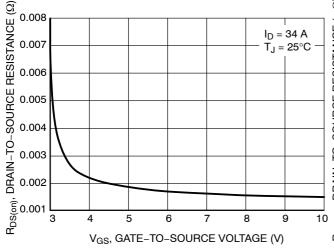
TYPICAL CHARACTERISTICS



200 $V_{DS} \ge 10 \text{ V}$ 180 160 ID, DRAIN CURRENT (A) 140 120 100 $T_J = -55^{\circ}C$ 80 60 $T_J = 25^{\circ}C$ 40 20 $T_J = 125^{\circ}C$ 0 1.5 2 2.5 3.5 4.5 V_{GS}, GATE-TO-SOURCE VOLTAGE (V)

Figure 1. On-Region Characteristics

Figure 2. Transfer Characteristics



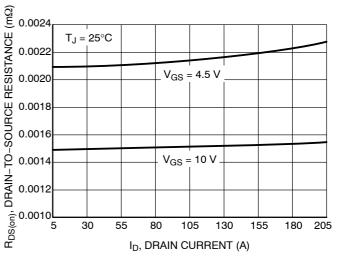
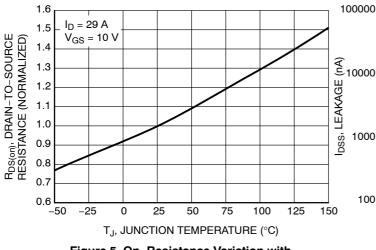


Figure 3. On-Resistance vs. Gate-to-Source Voltage

Figure 4. On-Resistance vs. Drain Current and Gate Voltage



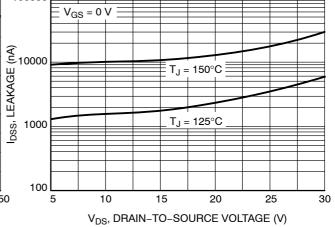


Figure 5. On–Resistance Variation with Temperature

Figure 6. Drain-to-Source Leakage Current vs. Voltage

TYPICAL CHARACTERISTICS

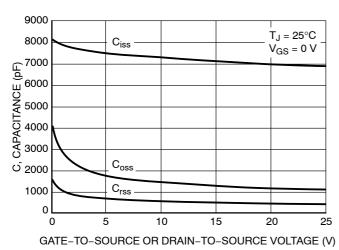


Figure 7. Capacitance Variation

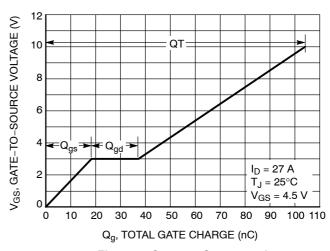


Figure 8. Gate-to-Source and Drain-to-Source Voltage vs. Total Charge

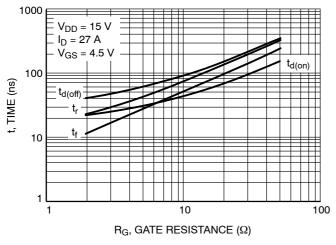


Figure 9. Resistive Switching Time Variation vs. Gate Resistance

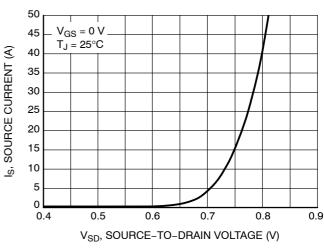


Figure 10. Diode Forward Voltage vs. Current

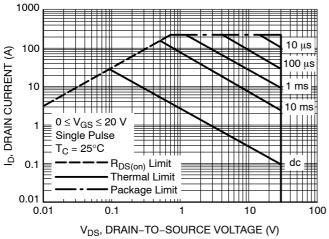


Figure 11. Maximum Rated Forward Biased Safe Operating Area

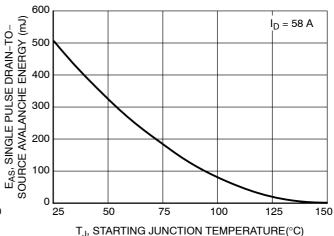


Figure 12. Maximum Avalanche Energy vs. Starting Junction Temperature

TYPICAL CHARACTERISTICS

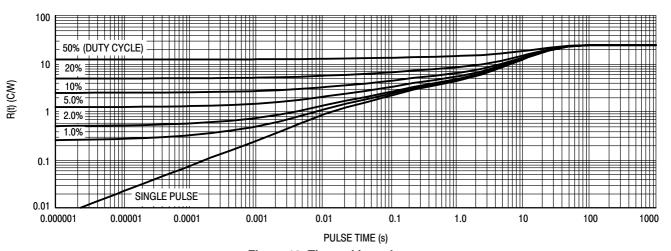
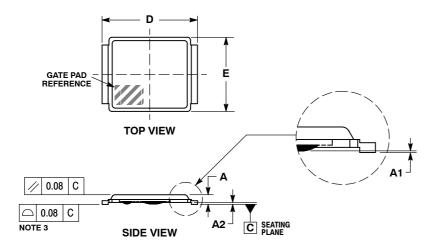


Figure 13. Thermal Impedance

PACKAGE DIMENSIONS

ICEPAK 6.3x4.9 - E PAD CASE 145AB-01 **ISSUE O**



NOTES:

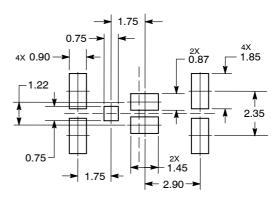
- 1. DIMENSIONING AND TOLERANCING PER
- ASME Y14.5M, 1994.
 CONTROLLING DIMENSION: MILLIMETERS.
 COPLANARITY APPLIES TO THE FLANGES OF LEADFRAME ONLY.

	MILLIMETERS		
DIM	MIN	MAX	
Α	0.61	0.68	
A1	0.02	0.08	
A2	0.08	0.17	
D	6.25	6.35	
D2	0.35	0.45	
D3	1.38	1.42	
D4	0.68	0.72	
E	4.80	5.05	
E2	3.85	3.95	
E3	0.80	0.84	
E4	0.68	0.72	
F	0.94 BSC		
G	2.54 BSC		
Н	0.38	0.42	

2X D3 DΔ D2 2X **E3 E2** 0.10 C A ○ 0.10 C A

BOTTOM VIEW

SOLDERING FOOTPRINT*



DIMENSIONS: MILLIMETERS

*For additional information on our Pb-Free strategy and soldering details, please download the ON Semiconductor Soldering and Mounting Techniques Reference Manual, SOLDERRM/D.

ON Semiconductor and un are registered trademarks of Semiconductor Components Industries, LLC (SCILLC). SCILLC reserves the right to make changes without further notice on semiconductor and are registered readerlands of semiconductor Components industries, Ite (SCILLC) solicit esserves the right to make changes without further holice to any products herein. SCILLC makes no warranty, representation or guarantee regarding the suitability of its products for any particular purpose, nor does SCILLC assume any liability arising out of the application or use of any product or circuit, and specifically disclaims any and all liability, including without limitation special, consequential or incidental damages. "Typical" parameters which may be provided in SCILLC data sheets and/or specifications can and do vary in different applications and actual performance may vary over time. All operating parameters, including "Typicals" must be validated for each customer application by customer's technical experts. SCILLC does not convey any license under its patent rights nor the rights of others. SCILLC products are not designed, intended, or authorized for use as components in systems intended for surgical implant into the body, or other applications intended to support or sustain life, or for any other application in which the failure of the SCILLC product could create a situation where personal injury or death may occur. Should Buyer purchase or use SCILLC products for any such unintended or unauthorized application, Buyer shall indemnify and hold SCILLC and its officers, employees, subsidiaries, affiliates, and distributors harmless against all claims, costs, damages, and expenses, and reasonable attorney fees arising out of, directly or indirectly, any claim of personal injury or death associated with such unintended or unauthorized use, even if such claim alleges that SCILLC was negligent regarding the design or manufacture of the part. SCILLC is an Equal Opportunity/Affirmative Action Employer. This literature is subject to all applicable copyright laws and is not for resale in any manner.

PUBLICATION ORDERING INFORMATION

LITERATURE FULFILLMENT:

Literature Distribution Center for ON Semiconductor P.O. Box 5163, Denver, Colorado 80217 USA **Phone**: 303-675-2175 or 800-344-3860 Toll Free USA/Canada Fax: 303-675-2176 or 800-344-3867 Toll Free USA/Canada Email: orderlit@onsemi.com

N. American Technical Support: 800-282-9855 Toll Free USA/Canada

Europe, Middle East and Africa Technical Support: Phone: 421 33 790 2910

Japan Customer Focus Center Phone: 81-3-5773-3850

ON Semiconductor Website: www.onsemi.com

Order Literature: http://www.onsemi.com/orderlit

For additional information, please contact your local Sales Representative